

Megaposit™ MF™-20A Developers

Improved Process Latitude for Both Conventional and Advanced Resists

Description

MEGAPOSIT MF-20A series Developers are surfactant containing developers, designed to provide improved process latitude for both conventional and advanced resists over a wide range of developer normalities.

Features Include

- Low-foaming formulation
- Developer normalities include: 0.21, 0.24, 0.26 and 0.27N
- Improved contrast for optimal lithographic performance
- Uniform resist development with minimal bubble and residue related defects
- Effective across various resist technologies (g-, g/h-, i-Line and DUV)

Lot-to-lot Consistency

- Tightly controlled product specifications
- Total systems functional testing
- Statistical process control

Manufacturing Process Control

Multiple Step In-process Testing

TMAH Normality First In-process Test

Carbonate

Second In-process Test **TMAH Normality**

Carbonate

Surface Tension

Packaging Approval* **TMAH Normality**

Carbonate

Particles

C of A**

Chloride

Metals

Color/Turbidity

TMAH Normality













the science of materials. the power of Collaboration

^{*}Normality controlled ±0.0002N

^{**}Control to ±0.0018 TMAH

Wide Process Latitude/High Throughput

MEGAPOSIT SPR™350-1.2 MEGAPOSIT SPR 850-1.0 Nominal 0.500 µm Nominal 0.400 µm Dense Lines/Spaces Dense Lines/Spaces Focus Latitude Focus Latitude Competitive Competitive 0.26N Developer MF-25A MF-26A 0.26N Developer -0.50-0.50-0.50-0.50 (0.532)(0.407)(0.542)(0.414)-0.30-0.30 -0.30 -0.30 (0.510)(0.521)(0.400)(0.393)-0.10 -0.10 -0.10 -0.10 (0.526)(0.503)(0.393)(0.400)Focus Offset, µm Focus Offset, µm +0.10 +0.10+0.10 +0.10(0.518)(0.517)(0.393)(0.400)+0.50 +0.50 +0.50 +0.50(0.483)(0.546)(0.408)(0.440)+0.60 +0.60 +0.60+0.60 (0.507)(0.640)(0.423)(0.524)+0.70+0.70 +0.70 +0.70 (0.524)(0.480)79 mJ/cm² 85 mJ/cm² 133 mJ/cm² 151 mJ/cm² Photospeed, E_0 Sizing Energy, E_s E_s/E_0 Ratio $\begin{array}{c} \text{Photospeed, E}_0 \\ \text{Sizing Energy, E}_s \end{array}$ 49 mJ/cm² 56 mJ/cm² 72 mJ/cm² 82 mJ/cm² 133 mJ/cm² 79 mJ/cm² 85 mJ/cm² 151 mJ/cm² E_s/E₀ Ratio Linearity @ E_s Resolution @ E_s 1.6 1.5 1.83 1.80 0.450 μm 0.400 µm Linearity @ Es 0.350 µm 0.375 µm 0.375 μm 0.400 µm Resolution @ E, 0.325 µm 0.350 µm Exposure Latitude ~28% ~ 22% Exposure Latitude ≥18.30% ≥16.23% Focus Latitude @ E_s 1.3 µm 1.0 µm Focus Latitude @ E_s $1.0\;\mu m$ 1.3 µm SUB 100 mm Silicon SUB = 100 mm Silicon 10,750Å, ±25Å 9,690Å, ±20Å = SB 90°C/60 sec. Contact Hotplate = 90°C/60 sec. Contact Hotplate

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ASM PAS5500/200 i-Line (0.57 NA, 0.60σ)

110°C/60 sec. Contact Hotplate

As Indicated/40 sec. SSP @ 21°C

EXP =

PFR

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EXP

PEB

DFV

=

ASM PAS5500/200 i-Line (0.57 NA, 0.60o)

110°C/60 sec. Contact Hotplate

As Indicated/30 sec. SSP